Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/820,933	MAKINO, HIDEYO	
Examiner	Art Unit	
Hai C. Pham	2861	

SEARCHED				
Class	Subclass	Date	Examiner	
347	241-242, 245, 256- 258, 263	2/25/2005	HP	
250	236	2/25/2005	НР	
20.				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH I (INCLUDING SEAR		<b>'</b> )
	DATE	EXMR
EAST	2/25/2005	НР